

Tuesday • April 4			
Time	Regency Main		
8:00 AM	Welcome & Introduction		
8:10 AM	Introduction to Technical Program		
8:30 AM	Keynote 1		
9:15 AM	Keynote 2		
10:00 AM	Awards		
10:15 AM	Break (20min)		
	Reg Main	Reg I	Reg IV
10:35 AM	2A - WBG	2B - PI	
10:40 AM	2A.1	2B.1	
11:05 AM	2A.2	2B.2	
11:30 AM	2A.3	2B.3	
11:55 AM	2A.4	2B.4	
12:20 PM	Break (20min) - Author's Corner		
12:40 PM	Roadmap Discussion (90min)*		
2:10 PM	2D - XT	2E - SER	2F - PV
2:15 PM	2D.1	2E.1	2F.1
2:40 PM	2D.2	2E.2	2F.2
3:05 PM	2D.3	2E.3	2F.3
3:30 PM	Break (20min) - Author's Corner		
3:50 PM	2D.4	ESREF	2F.4
4:15 PM	2D.5	IPFA	2F.5
4:40 PM	2D.6		
5:05 PM	Break (20min) - Author's Corner		
5:25 PM	Adjourn		

6:30 PM	Workshops (6:30-9:30PM)
9:30 PM	

\* Panel presentation and discussion with International Roadmap of Devices and Systems (IRDS)

Keynote 1: Dr Nancy Currie-Gregg, NASA Astronaut, and NESC principle engineer, "NASA human exploration missions and reliability challenges"

Keynote 2: Ronald Newhart, IBM Distinguished Engineer, "system level reliability challenges with technology scaling"

Wednesday • April 5			
Time	Reg Main	Reg I	Reg IV
8:00 AM	3A - PR	3B - WBG	3C - FEOL
8:05 AM	3A.1	3B.1	3C.1
8:30 AM	3A.2	3B.2	3C.2
8:55 AM	3A.3	3B.3	3C.3
9:20 AM	3A.4	3B.4	3C.4
9:45 AM	3A.5	3B.5	3C.5
10:10 AM	Break (30min) - Author's Corner		
10:40 AM	3D - SER	3E - RT	3F - ESD
10:45 AM	3D.1	3E.1	3F.1
11:10 AM	3D.2	3E.2	3F.2
11:35 AM	3D.3	3E.3	3F.3
12:00 PM	3D.4	3E.4	
12:25 PM	Break (20min) - Author's Corner		
12:45 PM	Lunch (90min)		
2:15 PM	4A - 3D	4B - WBG	4C - CR
2:20 PM	4A.1	4B.1	4C.1
2:45 PM	4A.2	4B.2	4C.2
3:10 PM	4A.3	4B.3	4C.3
3:35 PM	Break (30min) - Author's Corner		
4:05 PM	4A.4	4B.4	4C.4
4:30 PM	4A.5	4B.5	4C.5
4:55 PM	4A.6		4C.6
5:20 PM	Break (20min) - Author's Corner		
5:40 PM	Adjourn		

6:30 PM	Poster Session (6:30-9:30PM)
9:30 PM	

3D 2.5D / 3D / Packaging  
 BEOL Back-End Dielectrics  
 CR Circuit Aging / Reliability  
 ESD Electrostatic Discharge  
 FA Failure Analysis  
 FEOL Front-End Dielectrics  
 MET Metallization Reliability  
 MY Memory Reliability  
 PI Process Integration

PR Product Reliability  
 PV Photovoltaics  
 RT Reliability Testing  
 SER Soft Errors  
 SYS System Reliability  
 WBG Wide Band Gap  
 XT Transistor Reliability  
 XT/BC Transistors - Beyond CMOS

Thursday • April 6			
Time	Reg Main	Reg I	Reg IV
8:00 AM	5A - MY	5B - BEOL	5C - FA
8:05 AM	5A.1	5B.1	5C.1
8:30 AM	5A.2	5B.2	5C.2
8:55 AM	5A.3	5B.3	5C.3
9:20 AM	5A.4	5B.4	5C.4
9:45 AM	5A.5		5C.5
10:10 AM	Break (30min) - Author's Corner		
10:40 AM	6A - XT/BC	6B - MET	6C - SYS
10:45 AM	6A.1	6B.1	6C.1
11:10 AM	6A.2	6B.2	6C.2
11:35 AM	6A.3	6B.3	6C.3
12:00 PM	Break (20min) - Author's Corner		
12:20 PM	Lunch (90min)		
1:50 PM	6A.4	6B.4	6C.4
2:15 PM	6A.5	6B.5	6C.5
2:40 PM	6A.6	6B.6	6C.6
3:05 PM		6B.7	6C.7
3:30 PM	Break (20min) - Author's Corner		
3:50 PM	Closing and 2018 Introduction		
4:15 PM	Adjourn		